



Integrated Device Technology, Inc.
2975 Stender Way, Santa Clara, CA - 95054

PRODUCT/PROCESS CHANGE NOTICE (PCN)

PCN #: L-0410-07 DATE: 11/4/04 Product Affected: Selected Logic Mil-Grade products Date Effective: February 3, 2005	MEANS OF DISTINGUISHING CHANGED DEVICES: <input type="checkbox"/> Product Mark <input type="checkbox"/> Back Mark <input checked="" type="checkbox"/> Date Code Prefix (Stepping) change from "K" or "P" to "PB". (Please see attachment for detail) <input type="checkbox"/> Other
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Contact: Bimla Paul Title: Quality Assurance Manager Phone #: (408)-654-6419 Fax #: (408)-492-8362 E-mail: bimla.paul@idt.com	Attachment: <input checked="" type="checkbox"/> Yes <input type="checkbox"/> No Samples: Available upon request
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DESCRIPTION AND PURPOSE OF CHANGE:

<input type="checkbox"/> Die Technology <input type="checkbox"/> Wafer Fabrication Process <input type="checkbox"/> Assembly Process <input type="checkbox"/> Equipment <input type="checkbox"/> Material <input type="checkbox"/> Testing <input checked="" type="checkbox"/> Manufacturing Site <input type="checkbox"/> Data Sheet <input type="checkbox"/> Other	Selected Logic Mil-Grade products will be transferred to IDT's wafer fab facility in Hillsboro, Oregon (Fab 4). There is no change in die technology. Please see attachment for the affected products.
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RELIABILITY/QUALIFICATION SUMMARY:
Please see attachment for qualification data.

CUSTOMER ACKNOWLEDGMENT OF RECEIPT:
 IDT records indicate that you require written notification of this change. Please use the acknowledgement below or E-Mail to grant approval or request additional information. If IDT does not receive acknowledgement within 30 days of this notice it will be assumed that this change is acceptable.
 IDT reserves the right to ship either version manufactured after the process change effective date until the inventory on the earlier version has been depleted.

Customer: _____	<input type="checkbox"/> <i>Approval for shipments prior to effective date.</i>
Name/Date: _____	E-Mail Address: _____
Title: _____	Phone# /Fax# : _____

CUSTOMER COMMENTS: _____

IDT ACKNOWLEDGMENT OF RECEIPT:

RECD. BY: _____	DATE: _____
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ATTACHMENT - PCN #: L-0410-07

PCN Type: Fab Location Change

Data Sheet Change: None

Detail of Change: Selected Logic Mil-Grade products will be transferred to IDT's wafer fab facility in Hillsboro, Oregon (Fab 4). There is no change in die technology. Please see below for the affected products:

Part Number	DSCC Part Number	Old Stepping	New Stepping
IDT54FCT245TDB	5962-9221401MRA	K, P	PB
IDT54FCT245ATDB	5962-9221403MRA	K, P	PB
IDT54FCT245CTDB	5962-9221405MRA	K, P	PB
IDT54FCT245TLB	5962-9221401M2A	K, P	PB
IDT54FCT245ATLB	5962-9221403M2A	K, P	PB
IDT54FCT245CTLB	5962-9221405M2A	K, P	PB
IDT54FCT574TDB	5962-9222201MRA	K, P	PB
IDT54FCT574ATDB	5962-9222203MRA	K, P	PB
IDT54FCT574CTDB	5962-9222205MRA	K, P	PB
IDT54FCT574TLB	5962-9222201M2A	K, P	PB
IDT54FCT574ATDB	5962-9222203M2A	K, P	PB
IDT54FCT574CTLB	5962-9222205M2A	K, P	PB

Qualification Plans: Following reliability tests were performed on the Mil-Grade parts.
The qualification results are as follow:

Test Description	Test Method	Required Sample/ # Fails	Test results (Mil-Grade)
Operating Life Test: Dynamic 184 hrs @ 150°C	Mil-Std 883 Method 1005	116/0	116/0
ESD Human Body Model	Mil-Std 883 Method 3015	3/0	2,500V
Latch up	EIA/JESD STD-78	6/0	6/0